

300W STEREO / 600W MONO PurePath™ HD ANALOG-INPUT POWER STAGE

FEATURES

- PurePath™ HD Enabled Integrated Feedback Provides:
 - Signal Bandwidth up to 80kHz for High Frequency Content From HD Sources
 - Ultralow 0.03% THD at 1W into 4Ω
 - Flat THD at all Frequencies for Natural Sound
 - 80dB PSRR (BTL, No Input Signal)
 - >100dB (A weighted) SNR
 - Click and Pop Free Startup
- Multiple Configurations Possible on the Same PCB With Stuffing Options:
 - Mono Parallel Bridge Tied Load (PBTL)
 - Stereo Bridge Tied Load (BTL)
 - 2.1 Single Ended Stereo Pair and Bridge Tied Load Subwoofer
 - Quad Single Ended Outputs
- Total Output Power at 10%THD+N
 - 600W in Mono PBTL Configuration
 - 300W per Channel in Stereo BTL Configuration
 - 145W per Channel in Quad Single Ended Configuration
- High Efficiency Power Stage (>88%) With 60-mΩ Output MOSFETs
- Two Thermally Enhanced Package Options:
 - PHD (64-Pin QFP)
 - DKD (44-Pin PSOP3)
- Self-Protection Design (Including Undervoltage, Overtemperature, Clipping, and Short-Circuit Protection) With Error Reporting
- EMI Compliant When Used With Recommended System Design

APPLICATIONS

- Mini Combo System
- AV Receivers
- DVD Receivers
- Active Speakers

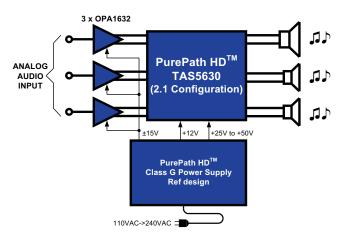
DESCRIPTION

The TAS5630 is a high performance analog input Class D amplifier with integrated closed loop feedback technology (known as PurePathTM HD) with the ability to drive up to 300W ⁽¹⁾ Stereo into 4 to 8 Ω Speakers from a single 50V supply.

PurePath[™] HD technology enables traditional AB-Amplifier performance (<0.03% THD) levels while providing the power efficiency of traditional class D amplifiers.

Unlike traditional Class D amplifiers, the distortion curve only increases once the output levels move into clipping.

PurePath[™] HD technology enables lower idle losses making the device even more efficient. Coupled with Tl's Class G power supply reference design for TAS563x, industry leading levels of efficiency can be achieved.



(1) Achievable output power levels are dependent on the thermal configuration of the target application. A high performance thermal interface material between the package exposed heatslug and the heat sink should be used to achieve high output power levels.

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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

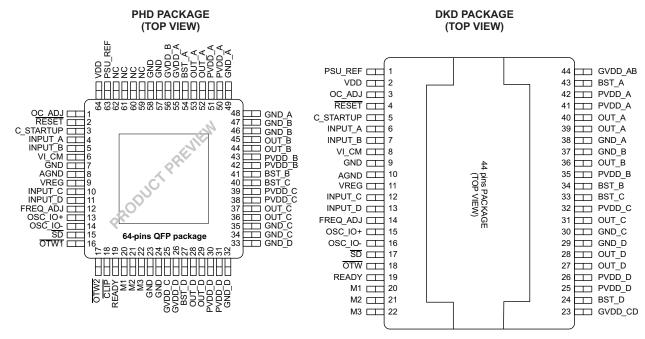
DEVICE INFORMATION

Terminal Assignment

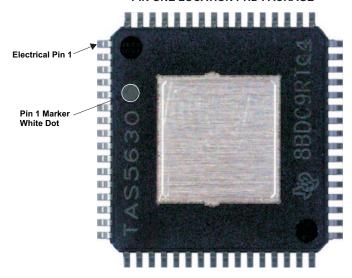
The TAS5630 is available in two thermally enhanced packages:

- 64-Pin QFP (PHD) Power Package
- 44-Pin PSOP3 package (DKD)

The package types contain heat slugs that are located on the top side of the device for convenient thermal coupling to the heat sink.



PIN ONE LOCATION PHD PACKAGE



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MODE SELECTION PINS

М	ODE PI	NS	ANALOG INPUT	OUTPUT		DESCR	DESCRIPTION		
М3	M2	M1	ANALOG INPUT	CONFIGURATION		IFTION			
0	0	0	Differential	2 × BTL	AD mode				
0	0	1	_	_	Reserved				
0	1	0	Differential	2 × BTL	BD mode				
0	1	1	Differential Single Ended	1 x BTL +2 xSE	BD mode, BTL Differential				
1	0	0	Single Ended	4 × SE	AD mode	AD mode			
					INPUT_C (1)	INPUT_D (1)			
1	0	1	Differential	1 × PBTL	0	0	AD mode		
					1	0	BD mode		
1	1	0			Decembed				
1	1	1		Reserved					

⁽¹⁾ INPUT_C and D are used to select between a subset of AD and BD mode operations in PBTL mode (1=VREG and 0=AGND).

PACKAGE HEAT DISSIPATION RATINGS(1)

PARAMETER	TAS5630PHD	TAS5630DKD
R _{0JC} (°C/W) – 2 BTL or 4 SE channels	2.63	1.4
R ₀ JC (°C/W) – 1 BTL or 2 SE channel(s)	4.13	2.04
R _{0JC} (°C/W) – 1 SE channel	6.45	3.45
Pad Area (2)	64 mm ²	80 mm ²

⁽¹⁾ J_C is junction-to-case, CH is case-to-heat sink

ORDERING INFORMATION(1)

T _A	PACKAGE	DESCRIPTION
0°C-70°C	TAS5630PHD ⁽²⁾	64 pin HTQFP
0°C-70°C	TAS5630DKD	44 pin PSOP3

For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI
website at www.ti.com.

(2) Product Preview

⁽²⁾ R_{0CH} is an important consideration. Assume a 2-mil thickness of thermal grease with a thermal conductivity of 2.5 W/mK between the pad area and the heat sink and both channels active. The R_{0CH} with this condition is 1.1°C/W for the PHD package and 0.44°C/W for the DKD package.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted (1)

		VALUE	UNIT
VDD to AGND		-0.3 to 13.2	V
GVDD to AGND		-0.3 to 13.2	V
PVDD_X to GND_X ⁽²⁾		-0.3 to 69	V
OUT_X to GND_X ⁽²⁾		-0.3 to 69	V
BST_X to GND_X ⁽²⁾		-0.3 to 82.2	V
BST_X to GVDD_X ⁽²⁾		-0.3 to 69	V
VREG to AGND		-0.3 to 4.2	V
GND_X to GND		-0.3 to 0.3	V
GND_X to AGND		-0.3 to 0.3	V
OC_ADJ, M1, M2, M3, OSC_IO+, OSC_IO to AGND)-, FREQ_ADJ, VI_CM, C_STARTUP, PSU_REF	-0.3 to 4.2	V
INPUT_X		-0.3 to 5	V
RESET, SD, OTW1, OTW2, CLIP, READY	to AGND	-0.3 to 7	V
Continuous sink current (SD, OTW1, OTW	2, CLIP, READY)	9	mA
Operating junction temperature range, T _J		0 to 150	°C
Storage temperature, T _{stg}		-40 to 150	°C
Floatroatatia diasharaa	Human body model ⁽³⁾ (all pins)	±2	kV
Electrostatic discharge	Charged device model (3) (all pins)	±500	V

Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. These voltages represents the DC voltage + peak AC waveform measured at the terminal of the device in all conditions.

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
PVDD_x	Half-bridge supply	DC supply voltage	25	50	52.5	V
GVDD_x	Supply for logic regulators and gate-drive circuitry	DC supply voltage	10.8	12	13.2	V
VDD	Digital regulator supply voltage	DC supply voltage	10.8	12	13.2	V
R _L (BTL)			3.5	4		
R _L (SE)	Load impedance	Output filter according to schematics in the application information section	1.8	2		Ω
R _L (PBTL)	upply for logic regulators and gate-drive ircuitry igital regulator supply voltage oad impedance utput filter inductance WM frame rate selectable for AM sterference avoidance; 1% Resistor olerance. WM frame rate programming resistor oltage on FREQ_ADJ pin for slave mode peration	are approach memater section	1.6	2		
L _{OUTPUT} (BTL)			7	10		
L _{OUTPUT} (SE)	Output filter inductance	Minimum output inductance at I _{OC}	7	15		μΗ
L _{OUTPUT} (PBTL)			7	10		
	PWM frame rate selectable for AM	Nominal	350	400	450	
F_{PWM}	interference avoidance; 1% Resistor	AM1	310	340	350	kHz
	tolerance.	AM2	250	300	320	
		Nominal; Master mode	9.5	10	10.5	
R_{FREQ_ADJ}	PWM frame rate programming resistor	AM1; Master mode	19.8	25 50 52.3 10.8 12 13.3 10.8 12 13.3 1.8 2 1.6 2 7 10 7 15 7 10 350 400 450 310 340 351 250 300 320 9.5 10 10.3 19.8 20 20.3 29.7 30 30.3 3.3	20.2	kΩ
		AM2; Master mode	29.7	30	30.3	
V _{FREQ_ADJ}	Voltage on FREQ_ADJ pin for slave mode operation	Slave mode		3.3		V
TJ	Junction temperature		0		150	°C

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Failure to follow good anti-static ESD handling during manufacture and rework will contribute to device malfunction. Please ensure operators handling the device are adequately grounded through the use of ground straps or alternative ESD protection.

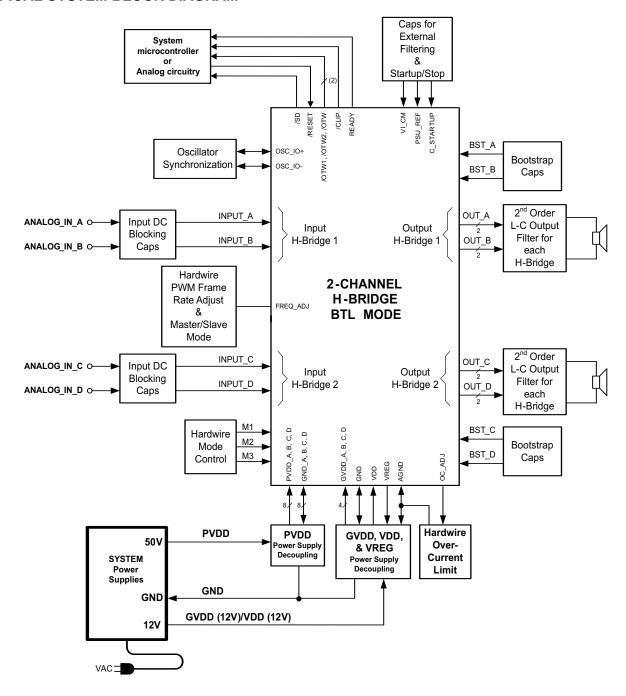
PIN FUNCTIONS

PIN			Function ⁽¹⁾	DESCRIPTION		
NAME	PHD NO.	DKD NO.	runction"	DESCRIPTION		
AGND	8	10	Р	Analog ground		
BST_A	54	43	Р	HS bootstrap supply (BST), external 0.033 μF capacitor to OUT_A required.		
BST_B	41	34	Р	HS bootstrap supply (BST), external 0.033 μF capacitor to OUT_B required.		
BST_C	40	33	Р	HS bootstrap supply (BST), external 0.033 μF capacitor to OUT_C required.		
BST_D	27	24	Р	HS bootstrap supply (BST), external 0.033 μF capacitor to OUT_D required.		
CLIP	18	_	0	Clipping warning; open drain; active low		
C_STARTUP	3	5	0	Startup ramp requires a charging capacitor of 4.7 nF to AGND in BTL mode		
FREQ_ADJ	12	14	I	PWM frame rate programming pin requires resistor to AGND		
GND	7, 23, 24, 57, 58	9	Р	Ground		
GND_A	48, 49	38	Р	Power ground for half-bridge A		
GND_B	46, 47	37	Р	Power ground for half-bridge B		
GND_C	34, 35	30	Р	Power ground for half-bridge C		
GND_D	32, 33	29	Р	Power ground for half-bridge D		
GVDD_A	55	_	Р	Gate drive voltage supply requires 0.1 μF capacitor to GND_A		
GVDD_B	56	_	Р	Gate drive voltage supply requires 0.1 μF capacitor to GND_B		
GVDD_C	25	_	Р	Gate drive voltage supply requires 0.1 μF capacitor to GND_C		
GVDD_D	26	_	Р	Gate drive voltage supply requires 0.1 μF capacitor to GND_D		
GVDD_AB	_	44	Р	Gate drive voltage supply requires 0.22 μF capacitor to GND_A/GND_B		
GVDD_CD	_	23	Р	Gate drive voltage supply requires 0.22 μF capacitor to GND_C/GND_D		
INPUT_A	4	6	I	Input signal for half bridge A		
INPUT_B	5	7	I	Input signal for half bridge B		
INPUT_C	10	12	I	Input signal for half bridge C		
INPUT_D	11	13	I	Input signal for half bridge D		
M1	20	20	I	Mode selection		
M2	21	21	I	Mode selection		
M3	22	22	I	Mode selection		
NC	59–62	_	_	No connect, pins may be grounded.		
OC_ADJ	1	3	0	Analog overcurrent programming pin requires resistor to AGND. 64 pin package (PHD) = 22kOhm. 44 pin PSOP3 (DKD) = 24kOhm		
OSC_IO+	13	15	I/O	Oscillator master/slave output/input.		
OSC_IO-	14	16	I/O	Oscillator master/slave output/input.		
OTW		18	0	Overtemperature warning signal, open drain, active low.		
OTW1	16		0	Overtemperature warning signal, open drain, active low.		
OTW2	17		0	Overtemperature warning signal, open drain, active low.		
OUT_A	52, 53	39, 40	0	Output, half bridge A		
OUT_B	44, 45	36	0	Output, half bridge B		
OUT_C	36, 37	31	0	Output, half bridge C		
OUT_D	28, 29	27, 28	0	Output, half bridge D		
PSU_REF	63	1	Р	PSU Reference requires close decoupling of 330 pF to AGND		
PVDD_A	50, 51	41, 42	Р	Power supply input for half bridges A requires close decoupling of 0.01 μF capacitor in parallel with 2.2 μF capacitor to GND_A		
PVDD_B	42, 43	35	Р	Power supply input for half bridges B requires close decoupling of 0.01 μF capacitor in parallel with 2.2 μF capacitor to GND_B		
PVDD_C	38, 39	32	Р	Power supply input for half bridges C requires close decoupling of 0.01 μ F capacitor in parallel with 2.2 μ F capacitor to GND_C		

PIN FUNCTIONS (continued)

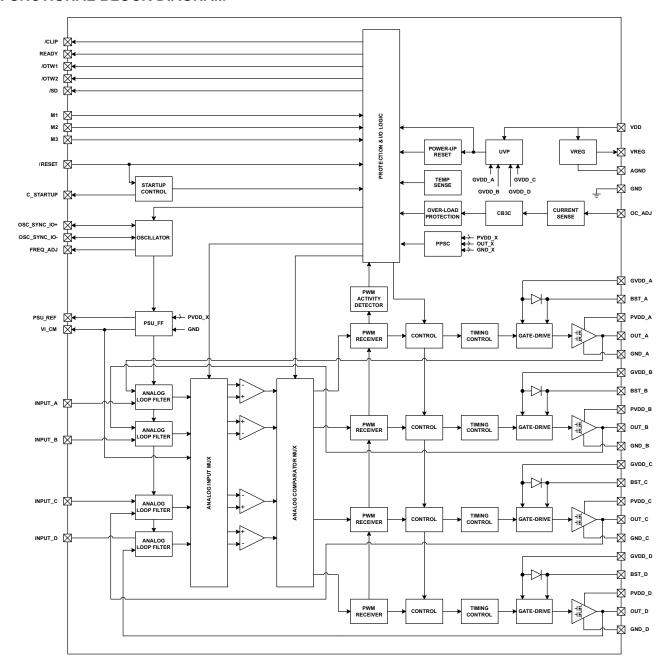
	PIN	PIN		DESCRIPTION
NAME	PHD NO.	DKD NO.	Function ⁽¹⁾	DESCRIPTION
PVDD_D	30, 31	25, 26	Р	Power supply input for half bridges A requires close decoupling of 0.01 μF capacitor in parallel with 2.2 μF capacitor to GND_A
READY	19	19	0	Normal operation; open drain; active high
RESET	2	4	I	Device reset Input; active low
SD	15	17	0	Shutdown signal, open drain, active low
VDD	64	2	Р	Power supply for digital voltage regulator requires a 10-μF capacitor in parallel with a 0.1-μF capacitor to GND for decoupling.
VI_CM	6	8	0	Analog comparator reference node requires close decoupling of 1nF to AGND
VREG	9	11	Р	Digital regulator supply filter pin requires 0.1-μF capacitor to AGND

TYPICAL SYSTEM BLOCK DIAGRAM





FUNCTIONAL BLOCK DIAGRAM



AUDIO CHARACTERISTICS (BTL)

PCB and system configuration are in accordance with recommended guidelines. Audio frequency = 1kHz, PVDD_X = 50 V, GVDD_X = 12 V, $R_L = 4\Omega$, $f_S = 400$ kHz, $R_{OC} = 22$ k Ω , $T_C = 75$ °C, Output Filter: $L_{DEM} = 7$ μ H, $C_{DEM} = 680$ nF, MODE = 010, unless otherwise noted.

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
THD+N Vn IVosI SNR DNR		$R_L = 4 \Omega$, 10% THD+N, clipped output signal	300		
		$R_L = 6 \Omega$, 10% THD+N, clipped output signal	210		
	Dower output per channel	$R_L = 8 \Omega$, 10% THD+N, clipped output signal	160		W
	Power output per channel	$R_L = 4 \Omega$, 1% THD+N, unclipped output signal	240		VV
		R_L = 6 Ω , 1% THD+N, unclipped output signal			
		$R_L = 8 \Omega$, 1% THD+N, unclipped output signal	125		
THD+N	Total harmonic distortion + noise	1 W	0.03%		
V _n	Output integrated noise	A-weighted, AES17 filter, Input Capacitor Grounded	270		μV
V _{OS}	Output offset voltage	Inputs AC coupled to AGND	40	150	mV
SNR	Signal-to-noise ratio ⁽¹⁾	A-weighted, AES17 filter	100		dB
DNR	Dynamic range	A-weighted, AES17 filter	100		dB
P _{idle}	Power dissipation due to Idle losses (I _{PVDD_X})	P _O = 0, 4 channels switching ⁽²⁾	2.7		W

⁽¹⁾ SNR is calculated relative to 1% THD+N output level..

AUDIO SPECIFICATION (Single-Ended Output)

PCB and system configuration are in accordance with recommended guidelines. Audio frequency = 1kHz, PVDD_X = 50 V, GVDD_X = 12 V, R_L = 4 Ω , f_S = 400 kHz, R_{OC} = 22 k Ω , T_C = 75°C, Output Filter: L_{DEM} = 15 μ H, C_{DEM} = 470 μ F, MODE = 100, unless otherwise noted.

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
		$R_L = 2 \Omega$, 10% THD+N, clipped output signal	145		
THD+N V _n SNR DNR		$R_L = 3 \Omega$, 10% THD+N, clipped output signal	100		
	Power output per channel	$R_L = 4 \Omega$, 10% THD+N, clipped output signal	75		
	Tower output per channel	$R_L = 2 \Omega$, 1% THD+N, unclipped output signal	110		W
		$R_L = 3 \Omega$, 1% THD+N, unclipped output signal	75		
		$R_L = 4 \Omega$, 1% THD+N, unclipped output signal	55		
THD+N	Total harmonic distortion + noise	1 W	0.07%		
V _n	Output integrated noise	A-weighted, AES17 filter, Input Capacitor Grounded	340		μV
SNR	Signal to noise ratio ⁽¹⁾	A-weighted, AES17 filter	93		dB
DNR	Dynamic range	A-weighted, AES17 filter	93		dB
P _{idle}	Power dissipation due to idle losses (I _{PVDD_X})	P _O = 0, 4 channels switching ⁽²⁾	2		W

⁽¹⁾ SNR is calculated relative to 1% THD+N output level.

Product Folder Link(s): TAS5630

⁽²⁾ Actual system idle losses also are affected by core losses of output inductors.

⁽²⁾ Actual system idle losses are affected by core losses of output inductors.



AUDIO SPECIFICATION (PBTL)

PCB and system configuration are in accordance with recommended guidelines. Audio frequency = 1kHz, PVDD_X = 50 V, GVDD_X = 12 V, $R_L = 2\Omega$, $f_S = 400$ kHz, $R_{OC} = 22$ k Ω , $T_C = 75$ °C, Output Filter: $L_{DEM} = 7$ μ H, $C_{DEM} = 1.5$ μ F, MODE = 101-10, unless otherwise noted.

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
THD+N V _n SNR DNR		$R_L = 2 \Omega$, 10% THD+N, clipped output signal	600		
		$R_L = 3 \Omega$, 10% THD+N, clipped output signal	400		
	Power output per channel	$R_L = 4 \Omega$, 10% THD+N, clipped output signal			W
		R _L = 2 Ω, 1% THD+N, unclipped output signal	480		VV
		$R_L = 3 \Omega$, 1% THD+N, unclipped output signal	310		
		$R_L = 4 \Omega$, 1% THD+N, unclipped output signal	230		
THD+N	Total harmonic distortion + noise	1 W	0.05%		
V _n	Output integrated noise	A-weighted	260		μV
SNR	Signal to noise ratio ⁽¹⁾	A-weighted	100		dB
DNR	Dynamic range	A-weighted	100		dB
P _{idle}	Power dissipation due to idle losses (IPVDD_X)	P _O = 0, 4 channels switching ⁽²⁾	2.7		W

⁽¹⁾ SNR is calculated relative to 1% THD-N output level.

ELECTRICAL CHARACTERISTICS

 $PVDD_X = 50 \text{ V, } GVDD_X = 12 \text{ V, } VDD = 12 \text{ V, } T_{C} \text{ (Case temperature)} = 75^{\circ}\text{C, } f_{S} = 400 \text{ kHz, unless otherwise specified.}$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
INTERNAL V	OLTAGE REGULATOR AND CURRENT CONSU	IMPTION	Į.		,	
VREG	Voltage regulator, only used as reference node, VREG	VDD = 12 V	3	3.3	3.6	V
VI_CM	Analog comparator reference node, VI_CM		1.5	1.75	1.9	V
	VDD averally averaged	Operating, 50% duty cycle		22.5		A
I _{VDD}	VDD supply current	Idle, reset mode		22.5		mA
1	CV/DD sets ourselv ourset set helf heiden	50% duty cycle		12.5		A
I _{GVDD_X}	GVDD_x gate-supply current per half-bridge	Reset mode		1.5		mA
I _{PVDD_X}	Half-bridge supply current	50% duty cycle with recommended output filter	13.3			mA
	C ,	Reset mode, No switching		870		μΑ
ANALOG IN	PUTS				,	
R _{IN}	Input resistance	READY = HIGH		33		kΩ
V _{IN}	Maximum input voltage swing			5		V
I _{IN}	Maximum input current			342		μΑ
G	Voltage Gain (V _{OUT} /V _{IN})			23		dB
OSCILLATO	R		Į.		· ·	
	Nominal, Master Mode		3.5	4	4.5	
f _{OSC_IO+}	AM1, Master Mode	F _{PWM} × 10	3.1	3.4	3.5	MHz
	AM2, Master Mode		2.6	3	_	
V _{IH}	High level input voltage		1.86			V
V _{IL}	Low level input voltage				1.45	V
OUTPUT-ST	AGE MOSFETs		I			
_	Drain-to-source resistance, low side (LS)	T _J = 25°C, excludes metallization		60	5 342 23 4 4.5 3.4 3.5 3 3.2 1.45	mΩ
R _{DS(on)}	Drain-to-source resistance, high side (HS)	resistance, GVDD = 12 V		60	100	mΩ

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⁽²⁾ Actual system idle losses are affected by core losses of output inductors.

ELECTRICAL CHARACTERISTICS (continued)

 $PVDD_X = 50 \text{ V}$, $GVDD_X = 12 \text{ V}$, VDD = 12 V, T_C (Case temperature) = 75°C, $f_S = 400 \text{ kHz}$, unless otherwise specified.

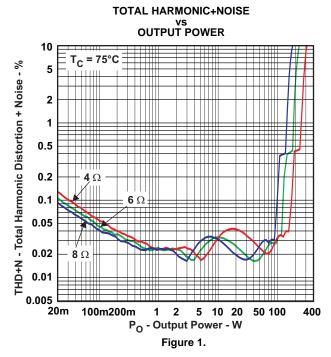
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I/O PROTECT	TION					
$V_{\text{uvp,G}}$	Undervoltage protection limit, GVDD_x and VDD			9.5		V
V _{uvp,hyst} ⁽¹⁾				0.6		V
OTW1 ⁽¹⁾	Overtemperature warning 1		95	100	105	°C
OTW2 ⁽¹⁾	Overtemperature warning 2		115	125	135	°C
OTW _{hyst} ⁽¹⁾	Temperature drop needed below OTW temperature for OTW to be inactive after OTW event.			25		°C
OTE ⁽¹⁾	Overtemperature error		145	155	165	°C
OIE ()	OTE-OTW differential			30		°C
OTE _{hyst} ⁽¹⁾	A reset needs to occur for $\overline{\text{SD}}$ to be released following an OTE event			25		°C
OLPC	Overload protection counter	f _{PWM} = 400 kHz		1.3		ms
	Overcurrent limit protection	Resistor – programmable, nominal peak current in 1Ω load, 64 Pin QFP package (PHD) $R_{OCP} = 22 \text{ k}\Omega$		19		Α
l _{oc}		Resistor – programmable, nominal peak current in 1Ω load, 44 Pin PSOP3 package (DKD), $R_{OCP} = 24 \text{ k}\Omega$		19		А
	Overcurrent limit protection, Latched	Resistor – programmable, nominal peak current in 1Ω load, $R_{OCP} = 47 \ k\Omega$		19		А
I _{OCT}	Overcurrent response time	Time from switching transition to flip-state induced by overcurrent		150		ns
I _{PD}	Internal pulldown resistor at output of each half bridge	Connected when RESET is active to provide bootstrap charge. Not used in SE mode.		3		mA
STATIC DIGIT	TAL SPECIFICATIONS					
V _{IH}	High level input voltage	INDUT V M4 M2 M2 DESET	2			V
V_{IL}	Low level input voltage	INPUT_X, M1, M2, M3, RESET			0.8	V
I_{lkg}	Input leakage current				100	μΑ
OTW/SHUTD	OWN (SD)					
R _{INT_PU}	Internal pullup resistance, $\overline{\text{OTW1}}$ to VREG, $\overline{\text{OTW2}}$ to VREG, $\overline{\text{SD}}$ to VREG		20	26	32	kΩ
V	High level output voltage	Internal pullup resistor	3	3.3	3.6	V
V _{OH}	High level output voltage	External pullup of 4.7 kΩ to 5 V	4.5		5	V
V_{OL}	Low level output voltage	I _O = 4 mA		200	500	mV
FANOUT	Device fanout OTW1, OTW2, SD, CLIP, READY	No external pullup		30		devices

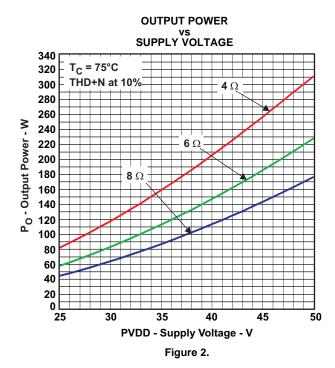
⁽¹⁾ Specified by design.

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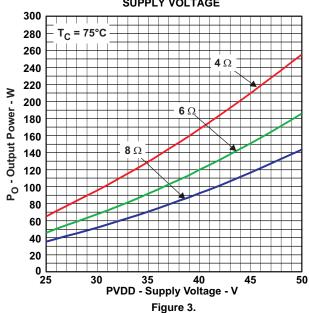
TEXAS INSTRUMENTS

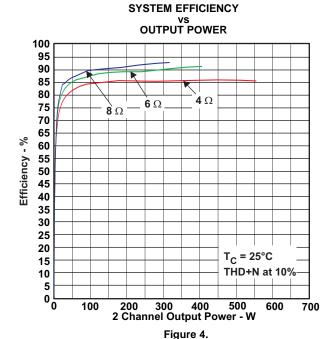
TYPICAL CHARACTERISTICS, BTL CONFIGURATION



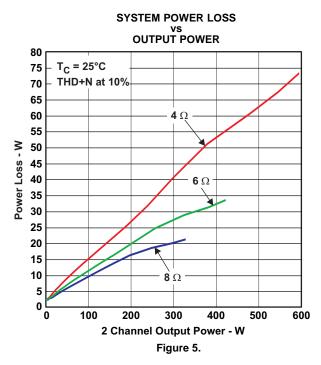


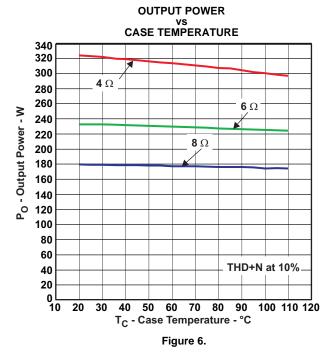
UNCLIPPED OUTPUT POWER
vs
SUPPLY VOLTAGE





TYPICAL CHARACTERISTICS, BTL CONFIGURATION (continued)

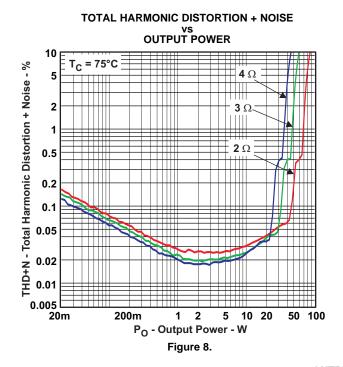


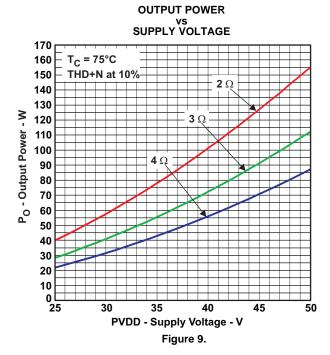


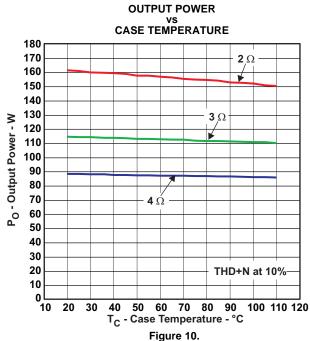
NOISE AMPLITUDE vs FREQUENCY $T_C = 75$ °C, -10 V_{REF} = 31.9 V, -20 Sample Rate = 48 kHz, -30 FFT Size = 16384 -40 Noise Amplitude - dB -50 -70 -80 -90 -110 -120 4Ω -130 -140 -150 -160^l 2k 4k 6k 8k 10k 12k 14k 16k 18k 20k 22k 0k f - Frequency - Hz Figure 7.



TYPICAL CHARACTERISTICS, SE CONFIGURATION



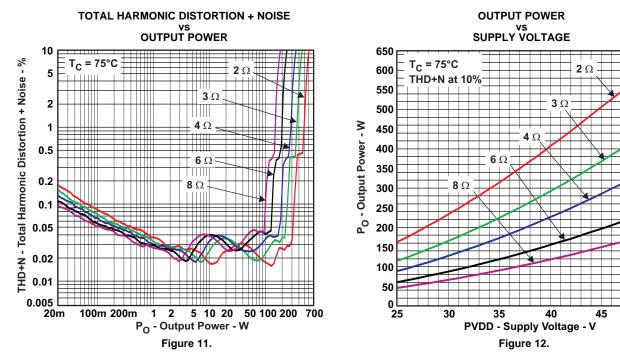


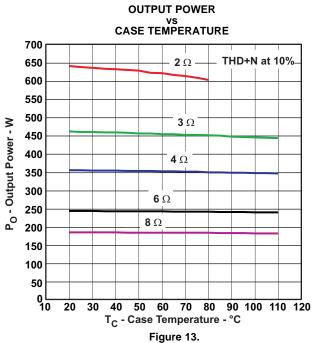


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TYPICAL CHARACTERISTICS, PBTL CONFIGURATION







APPLICATION INFORMATION

PCB MATERIAL RECOMMENDATION

FR-4 Glass Epoxy material with 2 oz. ($70\mu m$) is recommended for use with the TAS5630. The use of this material can provide for higher power output, improved thermal performance, and better EMI margin (due to lower PCB trace inductance).

PVDD CAPACITOR RECOMMENDATION

The large capacitors used in conjunction with each full-bridge, are referred to as the PVDD Capacitors. These capacitors should be selected for proper voltage margin and adequate capacitance to support the power requirements. In practice, with a well designed system power supply, $1000\mu F$, 63V will support more applications. The PVDD capacitors should be low ESR type because they are used in a circuit associated with high-speed switching.

DECOUPLING CAPACITOR RECOMMENDATIONS

To design an amplifier that has robust performance, passes regulatory requirements, and exhibits good audio performance, a quality decoupling capacitors should be used. In practice, X7R should be used in this application.

The voltage of the decoupling capacitors should be selected in accordance with good design practices. Temperature, ripple current, and voltage overshoot must be considered. This fact is particularly true in the selection of the $2.2\mu F$ that is placed on the power supply to each half-bridge. It must withstand the voltage overshoot of the PWM switching, the heat generated by the amplifier during high power output, and the ripple current created by high power output. A minimum voltage rating of 63 V is required for use with a 50V power supply.

SYSTEM DESIGN RECOMMENDATIONS

The following schematics and PCB layouts illustrate best practices used for the TAS5630.

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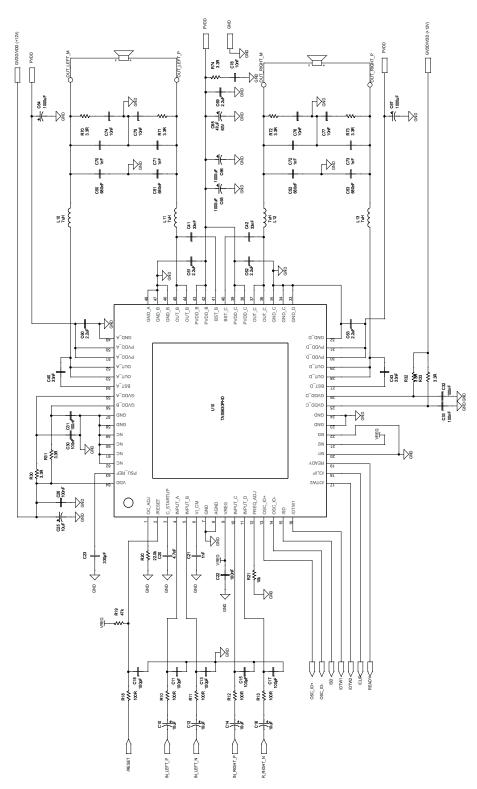


Figure 14. Typical Differential Input BTL Application With BD Modulation Filters



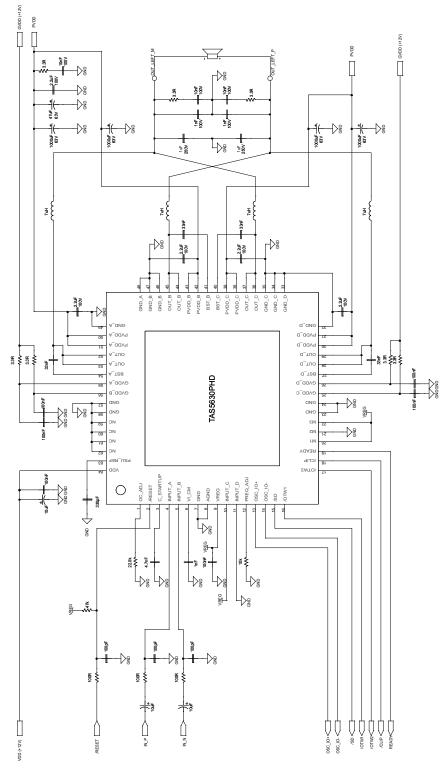


Figure 15. Typical Differential (2N) PBTL Application With BD Modulation Filters

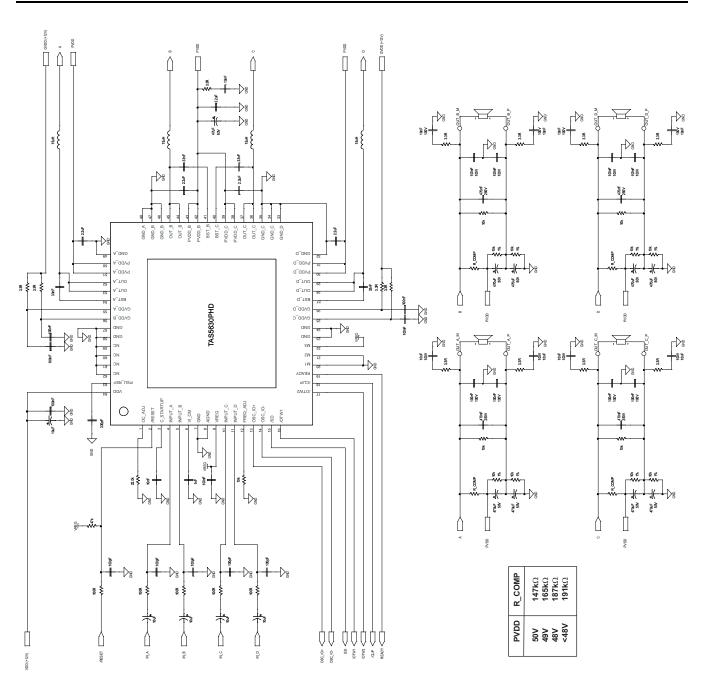


Figure 16. Typical SE Application



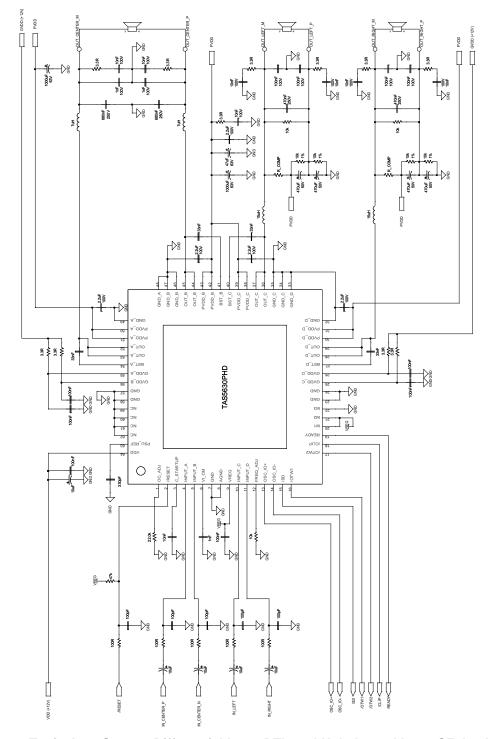


Figure 17. Typical 2.1 System Differential Input BTL and Unbalanced Input SE Application

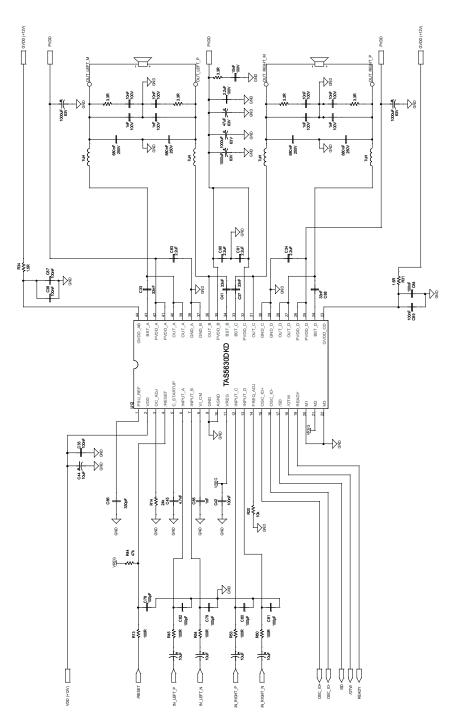


Figure 18. Typical Differential Input BTL Application With BD Modulation Filters DKD Package



THEORY OF OPERATION

POWER SUPPLIES

To facilitate system design, the TAS5630 needs only a 12V supply in addition to the (typical) 50V power-stage supply. An internal voltage regulator provides suitable voltage levels for the digital and low-voltage analog circuitry. Additionally, all circuitry requiring a floating voltage supply, e.g., the high-side gate drive, is accommodated by built-in bootstrap circuitry requiring only an external capacitor for each half-bridge.

To provide outstanding electrical and acoustical characteristics, the PWM signal path including gate drive and output stage is designed as identical, independent half-bridges. For this reason, each half-bridge has separate gate drive supply (GVDD_X), bootstrap pins (BST_X), and power-stage supply pins (PVDD_X). Furthermore, an additional pin (VDD) is provided as supply for all common circuits. Although supplied from the same 12V source, it is highly recommended to separate GVDD_A, GVDD_B, GVDD_C, GVDD_D, and VDD on the printed-circuit board (PCB) by RC filters (see application diagram for details). These RC filters provide the recommended high-frequency isolation. Special attention should be paid to placing all decoupling capacitors as close to their associated pins as possible. In general, inductance between the power supply pins and decoupling capacitors must be avoided. (See reference board documentation for additional information.)

For a properly functioning bootstrap circuit, a small ceramic capacitor must be connected from each bootstrap pin (BST_X) to the power-stage output pin (OUT_X). When the power-stage output is low, the bootstrap capacitor is charged through an internal diode connected between the gate-drive power-supply pin (GVDD_X) and the bootstrap pin. When the powerstage output is high, the bootstrap capacitor potential is shifted above the output potential and thus provides a suitable voltage supply for the high-side gate driver. In an application with PWM switching frequencies in the range from 300kHz to 400kHz, it is recommended to use 33nF ceramic capacitors, size 0603 or 0805, for the bootstrap supply. These 33nF capacitors ensure sufficient energy storage, even during minimal PWM duty cycles, to keep the high-side power stage FET (LDMOS) fully turned on during the remaining part of the PWM cycle.

Special attention should be paid to the power-stage power supply; this includes component selection, PCB placement, and routing. As indicated, each half-bridge has independent power-stage supply pins (PVDD_X). For optimal electrical performance, EMI compliance, and system reliability, it is important that each PVDD_X pin is decoupled with a 2.2µF ceramic capacitor placed as close as possible to each supply pin. It is recommended to follow the PCB layout of the TAS5630 reference design. For additional information on recommended power supply and required components, see the application diagrams in this data sheet.

The 12V supply should be from a low-noise, low-output impedance voltage regulator. Likewise, the 50V power-stage supply is assumed to have low output impedance and low noise. The power-supply sequence is not critical as facilitated by the internal power-on-reset circuit. Moreover, the TAS5630 is fully protected against erroneous power-stage turn on due to parasitic gate charging. Thus, voltage-supply ramp rates (dV/dt) are non-critical within the specified range (see the Recommended Operating Conditions table of this data sheet).

SYSTEM POWER-UP/POWER-DOWN SEQUENCE

Powering Up

The TAS5630 does not require a power-up sequence. The outputs of the H-bridges remain in a high-impedance state until the gate-drive supply voltage (GVDD_X) and VDD voltage are above the undervoltage protection (UVP) voltage threshold (see the <u>Electrical Characteristics</u> table of this data sheet). Although not specifically required, it is recommended to hold <u>RESET</u> in a low state while powering up the device. This allows an internal circuit to charge the external bootstrap capacitors by enabling a weak pulldown of the half-bridge output.

Powering Down

The TAS5630 does not require a power-down sequence. The device remains fully operational as long as the gate-drive supply (GVDD_X) voltage and VDD voltage are above the undervoltage protection (UVP) voltage threshold (see the Electrical Characteristics table of this data sheet). Although not specifically required, it is a good practice to hold RESET low during power down, thus preventing audible artifacts including pops or clicks.

Product Folder Link(s): TAS5630

ERROR REPORTING

The SD, OTW, OTW1 and OTW2 pins are active low, open-drain outputs. Their function is for protection-mode signaling to a PWM controller or other system-control device.

Any fault resulting in device shutdown is signaled by the SD pin going low. Likewise, OTW and OTW2 goes low when the device junction temperature exceeds 125°C and OTW1 goes low when the junction temperature exceeds 100°C (see the following table).

SD	OTW1	OTW2, OTW	DESCRIPTION				
0	0	0	Overtemperature (OTE) or overload (OLP) or undervoltage (UVP)				
0	0	1	Overload (OLP) or undervoltage (UVP). Junction temperature higher than 100°C (overtemperature warning)				
0	1	1	Overload (OLP) or undervoltage (UVP)				
1	0	0	Junction temperature higher than 125°C (overtemperature warning)				
1	0	1	Junction temperature higher than 100°C (overtemperature warning)				
1	1	1	Junction temperature lower than 100°C and no OLP or UVP faults (normal operation)				

Note that asserting either RESET low forces the SD signal high, independent of faults being present. TI recommends monitoring the OTW signal using the system microcontroller and responding to an overtemperature warning signal by, e.g., turning down the volume to prevent further heating of the device resulting in device shutdown (OTE).

To reduce external component count, an internal pullup resistor to 3.3V is provided on both SD and OTW outputs. Level compliance for 5V logic can be obtained by adding external pullup resistors to 5V (see the Electrical Characteristics tablen of this data sheet for further specifications).

DEVICE PROTECTION SYSTEM

The TAS5630 contains advanced protection circuitry carefully designed to facilitate system integration and ease of use, as well as to safeguard the device from permanent failure due to a wide range of fault conditions such as short circuits, overload, overtemperature, and undervoltage. The TAS5630 responds to a fault by immediately setting the power stage in a high-impedance (Hi-Z) state and asserting the SD pin low. In situations other than overload and overtemperature error (OTE), the device automatically recovers when the fault condition has been removed, i.e., the supply voltage has increased.

The device will function on errors, as shown in the following table.

BTL	Mode	PBTL	. Mode	SE Mode		
Local error in Turns Off or in		Local error in	Turns Off or in	Local error in	Turns Off or in	
Α	A+B	Α		Α	A . D	
В	A+D	В	A+B+C+D	В	A+B	
С	C.D	С	A+B+C+D	С	C.D	
D	- C+D	D		D	C+D	

Bootstrap UVP does not shutdown according to the table, it shuts down the respective halfbridge.

PIN-TO-PIN SHORT CIRCUIT PROTECTION (PPSC)

The PPSC detection system protects the device from permanent damage if a power output pin (OUT X) is shorted to GND_X or PVDD_X. For comparison, the OC protection system detects an over current after the demodulation filter where PPSC detects shorts directly at the pin before the filter. PPSC detection is performed at startup i.e. when VDD is supplied, consequently a short to either GND_X or PVDD_X after system startup will not activate the PPSC detection system. When PPSC detection is activated by a short on the output, all half bridges are kept in a Hi-Z state until the short is removed, the device then continues the startup sequence and starts switching. The detection is controlled globally by a two step sequence. The first step ensures that there are no shorts from OUT X to GND X, the second step tests that there are no shorts from OUT X to PVDD X. The total duration of this process is roughly proportional to the capacitance of the output LC filter. The typical duration is

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<15ms/µF. While the PPSC detection is in progress, SD is kept low, and the device will not react to changes applied to the RESET pins. If no shorts are present the PPSC detection passes, and SD is released. A device reset will not start a new PPSC detection. PPSC detection is enabled in BTL and PBTL output configurations, the detection is not performed in SE mode. To make sure the PPSC detection system is not tripped, it is recommended not to insert resistive load to GND_X or PVDD_X.

OVERTEMPERATURE PROTECTION

The two different package options has individual overtemperature protection schemes.

PHD Package:

The TAS5630 PHD package option has a three-level temperature-protection system that asserts an active low warning signal (OTW1) when the device junction temperature exceeds 100°C (typical), (OTW2) when the device junction temperature exceeds 125°C (typical) and, if the device junction temperature exceeds 155°C (typical), the device is <u>put</u> into thermal shutdown, resulting in all half-bridge outputs being set in the high-impedance (Hi-Z) state and SD being asserted low. OTE is latched in this case. To clear the OTE latch, RESET must be asserted. Thereafter, the device resumes normal operation.

DKD Package:

The TAS5630 DKD package option has a two-level temperature-protection system that asserts an active low warning signal (OTW) when the device junction temperature exceeds 125°C (typical) and, if the device junction temperature exceeds 155°C (typical), the device is put into thermal shutdown, resulting in all half-bridge outputs being set in the high-impedance (Hi-Z) state and SD being asserted low. OTE is latched in this case. To clear the OTE latch, RESET must be asserted. Thereafter, the device resumes normal operation.

UNDERVOLTAGE PROTECTION (UVP) AND POWER-ON RESET (POR)

The UVP and POR circuits of the TAS5630 fully protect the device in any power-up/down and brownout situation. While powering up, the POR circuit resets the overload circuit (OLP) and ensures that all circuits are fully operational when the GVDD_X and VDD supply voltages reach stated in the Electrical Characteristics table. Although GVDD_X and VDD are independently monitored, a supply voltage drop below the UVP threshold on any VDD or GVDD_X pin results in all half-bridge outputs immediately being set in the high-impedance (Hi-Z) state and SD being asserted low. The device automatically resumes operation when all supply voltages have increased above the UVP threshold.

DEVICE RESET

When RESET is asserted low, all power-stage FETs in the four half-bridges are forced into a high-impedance (Hi-Z) state.

In BTL modes, to accommodate bootstrap charging prior to switching start, asserting the reset input low enables weak pulldown of the half-bridge outputs. In the SE mode, the output is forced into a high impedance state when asserting the reset input low. Asserting reset input low removes any fault information to be signaled on the SD output, i.e., SD is forced high. A rising-edge transition on reset input allows the device to resume operation after an overload fault. To ensure thermal reliability, the rising edge of reset must occur no sooner than 4 ms after the falling edge of SD.

SYSTEM DESIGN CONSIDERATION

A rising-edge transition on reset input allows the device to execute the startup sequence and starts switching.

Apply only audio when the state of READY is high that will start and stop the amplifier without having audible artifacts that is heard in the output transducers. If an overcurrent protection event is introduced the READY signal goes low, hence, filtering is needed if the signal is intended for audio muting in non microcontroller systems.

The CLIP signal is indicating that the output is approaching clipping. The signal can be used to either an audio volume decrease or intelligent power supply controlling a low and a high rail.

The device is inverting the audio signal from input to output.

The VREG pin is not recommended to be used as a voltage source for external circuitry.

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OSCILLATOR

The oscillator frequency can be trimmed by external control of the FREQ ADJ pin.

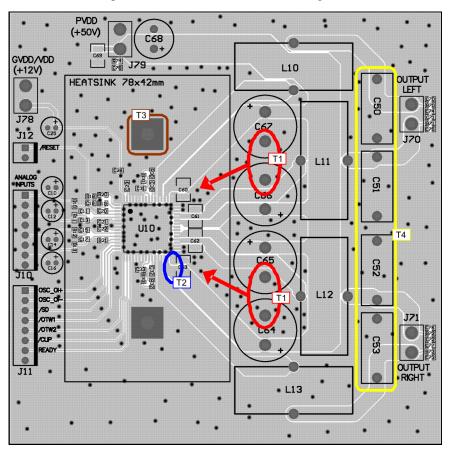
To reduce interference problems while using radio receiver tuned within the AM band, the switching frequency can be changed from nominal to lower values. These values should be chosen such that the nominal and the lower value switching frequencies together results in the fewest cases of interference throughout the AM band, and can be selected by the value of the FREQ ADJ resistor connected to AGND in master mode.

For slave mode operation, turn of the oscillator by pulling the FREQ_ADJ pin to VREG. This will configure the OSC I/O pins as inputs and needs to be slaved from an external clock.

PRINTED CIRCUIT BOARD RECOMMENDATION

Use an unbroken ground plane to have good low impedance and inductance return path to the power supply for power and audio signals. PCB layout, audio performance and EMI are linked closely together. The circuit contains high fast switching currents; therefore, care must be taken to prevent damaging voltage spikes. Routing the audio input should be kept short and together with the accompanied audio source ground. A local ground area underneath the device is important to keep solid to minimize ground bounce.

Netlist for this printed circuit board is generated from the schematic in Figure 14.



Note T1: PVDD decoupling bulk capacitors C60-C64 should be as close as possible to the PVDD and GND_X pins, the heat sink sets the distance. Wide traces should be routed on the top layer with direct connection to the pins and without going through vias. No vias or traces should be blocking the current path.

Note T2: Close decoupling of PVDD with low impedance X7R ceramic capacitors is placed under the heat sink and close to the pins.

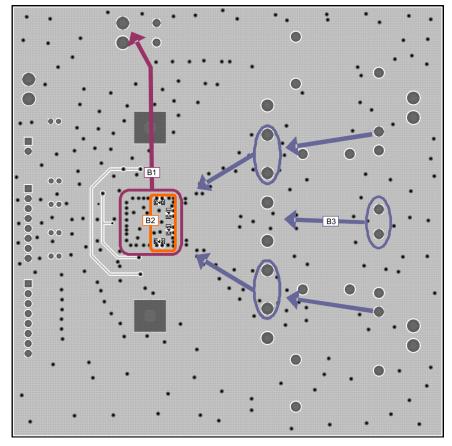
Note T3: Heat sink needs to have a good connection to PCB ground.

Note T4: Output filter capacitors must be linear in the applied voltage range preferable metal film types.

Figure 19. Printed Circuit Board - Top Layer







Note B1: It is important to have a direct low impedance return path for high current back to the power supply. Keep impedance low from top to bottom side of PCB through a lot of ground vias.

Note B2: Bootstrap low impedance X7R ceramic capacitors placed on bottom side providing a short low inductance current loop.

Note B3: Return currents from bulk capacitors and output filter capacitors.

Figure 20. Printed Circuit Board - Bottom Layer

PACKAGE OPTION ADDENDUM

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PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins F	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
TAS5630DKD	ACTIVE	HSSOP	DKD	44	29	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-4-260C-72 HR
TAS5630DKDR	ACTIVE	HSSOP	DKD	44	500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-4-260C-72 HR
TAS5630PHD	PREVIEW	HTQFP	PHD	64	90	TBD	Call TI	Call TI

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures. TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Dev	ice		Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TAS563	ODKDR	HSSOP	DKD	44	500	330.0	24.4	14.7	16.4	4.0	20.0	24.0	Q1

PACKAGE MATERIALS INFORMATION

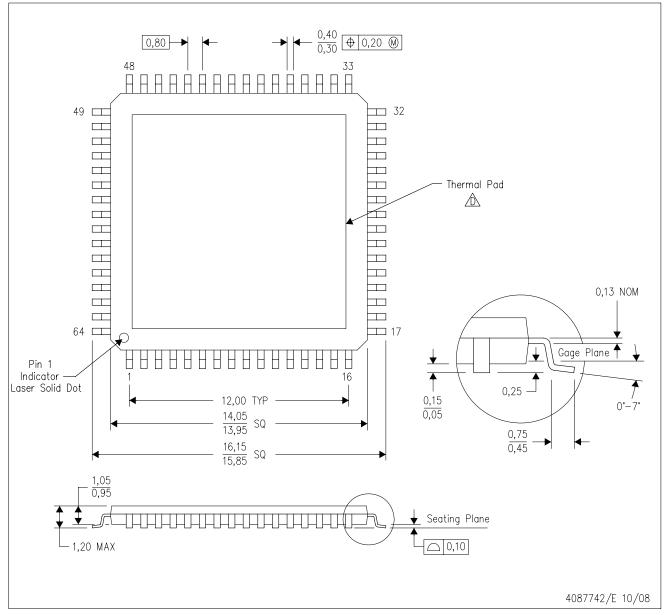
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*All dimensions are nominal

ĺ	Device	Device Package Type		Pins SPQ		Length (mm)	Width (mm)	Height (mm)	
	TAS5630DKDR	HSSOP	DKD	44	500	346.0	346.0	41.0	

PHD (S-PQFP-G64) PowerPAD™ PLASTIC QUAD FLATPACK (DIE DOWN)



NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion
- This package is designed to be attached directly to an external heatsink. Refer to Technical Brief, PowerPad Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 for information regarding recommended board layout. This document is available at www.ti.com http://www.ti.com. See the product data sheet for details regarding the exposed thermal pad dimensions.
- E. Falls within JEDEC MS-026

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